



Cypress Semiconductor Corporation, 198 Champion Court, San Jose, CA 95134. Tel: (408) 943-2600

## PRODUCT CHANGE NOTIFICATION

**PCN:** PCN182408

**Date:** June 17, 2018

**Subject:** Qualification of Fab 25 with the Copper (Cu) BEOL Process for the EZ-PD™ CCG4 (PD2) USB Type-C PD Controller Product Family

**To:** FUTURE ELECTRONICS  
FUTURE ELE  
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**Change Type:** Major

### **Description of Change:**

Cypress announces the qualification of Fab 25 in Austin, Texas with the Copper (Cu) Backend of Line (BEOL) process for the EZ-PD™ CCG4 (PD2) USB Type-C Power Delivery (PD) Controller product family.

The Aluminum (Al) BEOL process uses Tungsten (W) plugs and Ti/TiN/Al metallization with subtractive patterning to create the metal interconnect layers. The Cu BEOL process converts the underlying metal interconnect layers from W plugs to Cu plugs and from Ti/TiN/Al metallization with subtractive patterning to Cu damascene with Ta/TaN barriers.

This qualification is part of the flexible manufacturing initiative which allows Cypress to meet its delivery commitments in dynamic and changing market conditions.

### **Benefit of Change:**

Qualification of alternate manufacturing sites is part of the ongoing flexible manufacturing initiative announced by Cypress. The goal of the flexible manufacturing initiative is to provide the means for Cypress to continue to meet delivery commitments through dynamic, changing market conditions.

### **Part Numbers Affected: 6**

See the attached 'Affected Parts List' file for a list of all part numbers affected by this change. Note that any new parts that are introduced after the publication of this PCN will include all changes outlined in this PCN.

**Qualification Status:**

This wafer fab site has been qualified through a series of tests documented in the Qualification Test Plan QTP#174802. This qualification report can be found as an attachment to this PCN or by visiting [www.cypress.com](http://www.cypress.com) and typing the QTP number in the keyword search window.

**Sample Status:**

Qualification samples may not be built ahead of time for all part numbers affected by this change. Please review the attached 'Affected Parts List' file for a list of affected part numbers with their associated Fab 25 Cu BEOL sample ordering part numbers. Samples are available now unless there is an indication that the sample ordering part numbers are subject to lead times. If you require qualification samples, please contact your local Cypress sales representative as soon as possible, preferably within 30 days of the date of this PCN, to place any sample orders.

**Approximate Implementation Date:**

Effective 90 days from the date of this notification or upon customer approval, whichever comes first, all shipments of Commercial, Industrial and Automotive non-PPAP part numbers in the attached file will be supplied Fab 25 with Cu BEOL or Al BEOL process or other approved wafer fabrication sites.

**Anticipated Impact:**

Products fabricated at the new site are completely compatible with existing products from form, fit, functional, parametric and quality performance perspectives.

Cypress also recommends that customers take this opportunity to review these changes against current application notes, system design considerations and customer environment conditions to assess impact (if any) to their application.

**Method of Identification:**

Cypress maintains traceability of product to wafer level, including wafer fabrication location, through the lot number marked on the package.

**Response Required:**

No response is required.

For additional information regarding this change, contact your local sales representative or contact the PCN Administrator at [pcn\\_adm@cypress.com](mailto:pcn_adm@cypress.com).

Sincerely,

Cypress PCN Administration

<b>Item</b>	<b>Marketing Part Number</b>	<b>Sample Order Part Number</b>	<b>Package</b>
1	CYPD4125-40LQXI	CYPD41257-40LQXI	40-pin QFN
2	CYPD4125-40LQXIT	CYPD41257-40LQXI	40-pin QFN
3	CYPD4225-40LQXI	CYPD42257-40LQXI	40-pin QFN
4	CYPD4225-40LQXIT	CYPD42257-40LQXI	40-pin QFN
5	CP8691AT	CP8691XT	40-pin QFN
6	CP8691ATT	CP8691XT	40-pin QFN

# Cypress Semiconductor Product Qualification Report

**QTP# 174802 VERSION\*\***  
**June 2018**

<b>EZ-PD™ CCG4 (PD2) USB Two-Port Type-C PD Controller Device Family S8SPR1 Technology, Fab 25 (Cu BEOL Interconnect)</b>	
<b>CYPD4125**</b>	<b>EZ-PD™ CCG4 (PD2) Dual USB Type-C Controller</b>
<b>CYPD4225**</b>	

**FOR ANY QUESTIONS ON THIS REPORT, PLEASE CONTACT**  
[reliability@cypress.com](mailto:reliability@cypress.com) or via a CYLINK CRM CASE

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## PRODUCT QUALIFICATION HISTORY

QTP Number	Description of Qualification Purpose	Date
151008	Qualification of S8* Technology in Fab 25 Using TrueTouch® Gen6M Touchscreen Controller Device	Dec. 2015
151303	Qualification of CapSense® MBR3 Device, S8PF-10R Technology in Fab 25	Dec. 2015
160401	Qualification of TrueTouch® Fingerprint Device, S8PFHD-10R Technology in Fab 25	May 2016
160301	Qualification of TrueTouch® Gen6XL Touchscreen Controller Device, S8SPF-10P Technology in Fab 25	June 2016
160803	Qualification of PSoC® 4000S Device, S8PFHD-10R Technology in Fab 25	June 2016
160207	Qualification of PSoC® 3 Device, S8P12-10P Technology in Fab 25	July 2016
161003	Qualification of EZ-PD™ CCG1 USB Type-C PD Controller Device, S8PF-10R Technology in Fab 25	March 2016
160809	Qualification of EZ-PD™ CCG2 USB Type-C PD Controller Device, S8PR2-10R Technology in Fab 25	Aug. 2016
164802	Qualification of EZ-PD™ CCG2 USB Type-C PD Controller Device, S8PR1-10/S8PHR-10R Technology in Fab 25	Sept. 2017
163301	Qualification of EZ-PD™ CCG3 USB Type-C PD Controller Device, S8SPF-20/S8SPF20-NP Technology in Fab 25 (Al BEOL Interconnect)	June 2017
164302	Qualification of EZ-PD™ CCG3 USB Type-C PD Controller Device, S8SPF-20/S8SPF20-NP Technology in Fab 25 (Cu BEOL Interconnect)	Nov.2017
162113	Qualification of EZ-PD™ CCG4 USB Two-Port Type-C PD Controller Device, S8SPR1P Technology in Fab 25 (Al BEOL Interconnect)	March 2017
174801	Qualification of EZ-PD™ CCG4 (PD3) USB Two-Port Type-C PD Controller Device, S8SPR1 Technology in Fab 25 (Cu BEOL Interconnect)	Feb. 2018
174802	Qualification of EZ-PD™ CCG4 (PD2) USB Two-Port Type-C PD Controller Device, S8SPR1 Technology in Fab 25 (Cu BEOL Interconnect)	June 2018

<b>PRODUCT DESCRIPTION (for qualification)</b>	
Qualification Purpose: To qualify EZ-PD™ CCG4 (PD2) USB Two-Port Type-C PD Controller Device, S8SPR1 Technology in Fab 25 (Cu BEOL Interconnect)	
Marketing Part #:	CYPD4125**/ CYPD4225**
Device Description:	EZ-PD™ CCG4 (PD2) Dual USB Type-C Controller
Cypress Division:	Cypress Semiconductor – MCU and Connectivity Division (MCD)

<b>TECHNOLOGY/FAB PROCESS DESCRIPTION</b>			
Number of Metal Layers:	Proprietary	Metal Composition:	Proprietary
Passivation Type and Thickness:	Proprietary		
Generic Process Technology/Design Rule (μ-drawn):	Proprietary		
Gate Oxide Material/Thickness (MOS):	Proprietary		
Name/Location of Die Fab (prime) Facility:	Fab 25		
Die Fab Line ID/Wafer Process ID:	S8SPR1		

### ALTERNATIVE FAB FACILITY SITE

<b>FAB SITE</b>	<b>LOCATION</b>	<b>QTP NUMBER</b>
SkyWater	Bloomington, Minnesota	154601 (Al BEOL Interconnect)
Fab 25	Austin, Texas	162113 (Al BEOL Interconnect)
Fab 25	Austin, Texas	174801 (CCG4 PD3) (Cu BEOL Interconnect)

<b>MAJOR PACKAGE INFORMATION USED IN THIS QUALIFICATION</b>	
Package Designation:	LQ40
Package Outline, Type, or Name:	Quad Flat No Lead (QFN), 6x6x0.6mm
Mold Compound Name/Manufacturer:	GE7470L-A/Nitto
Mold Compound Flammability Rating:	V-0 UL94
Oxygen Rating Index: >28%	54%
Lead Frame Designation:	FMP
Lead Frame Material:	Copper
Lead Finish, Composition / Thickness:	NiPdAu
Die Backside Preparation Method/Metallization:	Backgrind
Die Separation Method:	Saw Process
Die Attach Supplier:	Henkel
Die Attach Material:	QMI 519
Bond Diagram Designation	001-99438
Wire Bond Method:	Thermosonic
Wire Material/Size:	CuPd/0.8 mil (20um)
Thermal Resistance Theta JA °C/W:	31 °C /W
Package Cross Section Yes/No:	Yes
Assembly Process Flow:	11-21099
Name/Location of Assembly (prime) facility:	CML-RA
MSL Level	3
Reflow Profile	260C

<b>ELECTRICAL TEST / FINISH DESCRIPTION</b>	
Test Location:	CML-RA

## RELIABILITY TESTS PERFORMED PER SPECIFICATION REQUIREMENTS

Stress/Test	Test Condition (Temp/Bias)	Result P/F
Acoustic Microscopy	J-STD-020 Precondition: JESD22 Moisture Sensitivity Level (192 Hrs., 30 °C, 60% RH, 260°C Reflow)	P
Data Retention	150°C/175°C, No Bias JESD22-A117 and JESD22-A103	P
Electrostatic Discharge Charge Device Model (ESD-CDM)	500V/750V/1,000V/1,250V/1,500V/1,750V/2,000V JESD22-C101	P
Electrostatic Discharge Human Body Model (ESD-HBM)	1,100V/2,200V /3,300V/4,000V/5,000V/6,000V/7,000V/8,000V JESD22, Method A114	P
Endurance Test	Per Datasheet (100K Cycles), JESD22-A117	P
High Accelerated Saturation Test (HAST)	JEDEC STD 22-A110: 130°C, 85% RH, 5.5V/6.6V Precondition: JESD22 Moisture Sensitivity Level (192 Hrs., 30 °C, 60% RH, 260°C Reflow)	P
High Temperature Operating Life Early Failure Rate	Dynamic Operating Condition, Vcc Max=2.07V/2.16V/2.27V/6.6V, 150°C JESD22-A-108	P
High Temperature Operating Life Latent Failure Rate	Dynamic Operating Condition, Vcc Max=2.07V/2.27V, 150°C JESD22-A-108	P
Low Temperature Operating Life	Dynamic Operating Condition, -40°C JESD22-A108	P
Pressure Cooker	JESD22-A102:121°C /100%RH, 15 PSIG Precondition: JESD22 Moisture Sensitivity Level (192 Hrs., 30 °C, 60% RH, 260°C Reflow)	P
SEM Analysis	MIL-STD-883, Method 2018	P
Static Latch-up	85°C, +/- 140mA, +/- 200mA, +/-300mA 125°C, +/-100mA, +/-140mA JESD 78	P
Temperature Cycle	MIL-STD-883, Method 1010, Condition C, -65°C to 150°C Precondition: JESD22 Moisture Sensitivity Level (192 Hrs., 30 °C, 60% RH, 260°C Reflow)	P



### RELIABILITY FAILURE RATE SUMMARY

Stress/Test	Device Tested/ Device Hours	# Fails	Activation Energy	Thermal AF <sup>3</sup>	Failure Rate
High Temperature Operating Life Early Failure Rate	1, 591 Devices	0	N/A	N/A	0 PPM <sup>(1)</sup>
High Temperature Operating Life Long Term Failure Rate	553,740 DHRs	0	0.7	170	10 FIT <sup>(2)</sup>

1. Early Failure Rate was computed from QTP# 174802.
2. Long Term Failure Rate was computed from QTP#151008, QTP#151303, QTP#160301, QTP#160207, QTP# 161003, QTP# 164802, QTP# 163301, QTP# 164302 data.

<sup>1</sup> Assuming an ambient temperature of 55°C and a junction temperature rise of 15°C.

<sup>2</sup> Chi-squared 60% estimations used to calculate the failure rate.

<sup>3</sup> Thermal Acceleration Factor is calculated from the Arrhenius equation

$$AF = \exp \left[ \frac{E_A}{k} \left[ \frac{1}{T_2} - \frac{1}{T_1} \right] \right]$$

where:

$E_A$  = The Activation Energy of the defect mechanism.

$K$  = Boltzmann's constant =  $8.62 \times 10^{-5}$  eV/Kelvin.

$T_1$  is the junction temperature of the device under stress and  $T_2$  is the junction temperature of the device at use conditions.



## Reliability Test Data

**QTP #: 151008**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: ACOUSTIC, MSL3</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	15	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	15	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	15	0	
<b>STRESS: DATA RETENTION, PLASTIC, 150C</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	80	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1000	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1000	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	80	0	
<b>STRESS: DATA RETENTION, PLASTIC, 175C</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	76	80	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	152	79	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	76	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	152	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	76	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	152	80	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150, 2.07V, Vcc Max)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	48	1490	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	48	1510	0	
CYTT214032 (8CP206101)	4545249	611537364	CML-RA	48	1547	0	
<b>STRESS: ENDURANCE</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	CYCLING	78	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	168	78	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	78	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	CYCLING	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	168	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	CYCLING	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	168	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	80	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	9	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	750	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1000	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1250	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1500	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1750	3	0	



## Reliability Test Data

**QTP #: 151008**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	9	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	750	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1000	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1250	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1500	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1750	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	9	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	750	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1000	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1250	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1500	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1750	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1100	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	2200	8	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	3300	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	4000	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	5000	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1100	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	2200	8	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	3300	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	4000	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1100	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	2200	8	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	3300	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	4000	3	0	
<b>STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	96	30	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	96	30	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	80	116	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	116	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	80	120	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	120	0	



## Reliability Test Data

**QTP #: 151008**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: LOW TEMPERATURE OPERATING LIFE, -40C</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	160	40	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	380	40	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	168	75	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	168	78	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	168	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	288	80	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	10+2	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	10+2	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	10+2	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	6	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	6	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	6	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	3	0	
<b>STRESS: SEM CROSS SECTION</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	1	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	80	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1000	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	79	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1000	79	0	
<b>STRESS: THERMAL JUNCTION MEASUREMENT</b>							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	1	0	



## Reliability Test Data

**QTP #: 151303**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: ACOUSTIC, MSL3</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	15	0	
<b>STRESS: DATA RETENTION, PLASTIC, 150C</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	500	80	0	
<b>STRESS: DATA RETENTION, PLASTIC, 175C</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	76	80	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	152	80	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	48	1469	0	
<b>STRESS: ENDURANCE</b>							
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	CYCLING	80	0	
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	168	80	0	
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	500	80	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	500	9	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	750	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1250	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1500	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1750	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1100	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	2200	8	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	3300	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	4000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	5000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	6000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	7000	3	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CY8CMBR31552(8CP44303CB)	4542914	611534693	ASE-G	80	120	0	
CY8CMBR31552(8CP44303CB)	4542914	611534693	ASE-G	500	120	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	168	80	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	288	79	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CY8CMBR31552(8CP44303CB)	4542914	611534693	ASE-G	COMP	10+2	0	



## Reliability Test Data

**QTP #: 151303**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	6	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	3	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	500	80	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1000	80	0	

## Reliability Test Data

**QTP #: 160401**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: ACOUSTIC, MSL3</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	15	0	
<b>STRESS: DATA RETENTION, PLASTIC, 150C</b>							
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	500	80	0	
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	1000	80	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	48	1550	0	
<b>STRESS: ENDURANCE</b>							
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	CYCLING	80	0	
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	168	80	0	
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	1000	80	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	500	9	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	750	3	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	1000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	1100	3	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	2200	3	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	3300	3	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	168	80	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	168	76	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	500	78	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	1000	76	0	

## Reliability Test Data

**QTP #: 160301**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: DATA RETENTION, PLASTIC, 150C</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	80	0	
<b>STRESS: DATA RETENTION, PLASTIC, 175C</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	76	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	152	80	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	48	2609	1	No Visual Defect found
CYAT816882 (8C206802BB)	3617006	611617664	CML-R	48	1013	0	
<b>STRESS: ENDURANCE</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	CYCLING	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	80	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	9	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	750	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	3	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	500	9	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1000	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1250	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1500	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1750	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1100	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	2200	8	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	3300	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	4000	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	5000	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	6000	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	7000	3	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	99	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	10	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	





## Reliability Test Data

**QTP #: 160301**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	80	0	



## Reliability Test Data

**QTP #: 160803**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
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**STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	48	1596	0	
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**STRESS: ESD-CHARGE DEVICE MODEL**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	500	9	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	750	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1250	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1500	3	0	

**STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1100	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	2200	8	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	3300	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	4000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	5000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	6000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	7000	3	0	

**STRESS: STATIC LATCH-UP (125C, 100mA)**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
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**STRESS: STATIC LATCH-UP (125C, 140mA)**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
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**STRESS: STATIC LATCH-UP (85C, 140mA)**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
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**STRESS: STATIC LATCH-UP (85C, 200mA)**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
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**STRESS: STATIC LATCH-UP (85C, 300mA)**

CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
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## Reliability Test Data

**QTP #: 160207**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: ACOUSTIC, MSL3</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	15	0	
<b>STRESS: DATA RETENTION, PLASTIC, 150C</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	1000	90	0	
<b>STRESS: DATA RETENTION, PLASTIC, 175C</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	76	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	152	90	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	48	2303	0	
<b>STRESS: ENDURANCE</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	CYCLING	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	168	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	90	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	9	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	1100	3	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	2200	8	0	
<b>STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	96	30	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	125	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	168	78	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	80	0	



## Reliability Test Data

**QTP #: 161003**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: ACOUSTIC, MSL3</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	COMP	15	0	
<b>STRESS: DATA RETENTION, PLASTIC, 150C</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	500	80	0	
<b>STRESS: DATA RETENTION, PLASTIC, 175C</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	76	80	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	152	80	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	48	1510	0	
<b>STRESS: ENDURANCE</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	CYCLING	80	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	168	80	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	500	80	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	500	9	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	750	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	1000	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	1250	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	1500	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	1750	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	1100	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	2200	8	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	3300	3	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	4000	3	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	80	120	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	500	120	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	168	80	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	288	80	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	COMP	10+2	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	COMP	6	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	COMP	3	0	

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## Reliability Test Data

**QTP #: 161003**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	COMP	3	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CYPD1103 (8F44100)	4537464	611531543	CML-R	500	79	0	
CYPD1103 (8F44100)	4537464	611531543	CML-R	1000	79	0	

## Reliability Test Data

**QTP #: 160809**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	500	9	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	750	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	1000	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	1250	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	1500	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	1750	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	1100	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	2200	8	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	3300	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	4000	3	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	5000	3	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150, 2.07V, Vcc Max)</b>							
CYPD21342 (7CP64111C)	3612012	611612816	CML-RA	48	1032	0	
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	48	537	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	COMP	3	0	
<b>YIELD: BACKEND</b>							
CYPD21342 (7CP64111C)	3612012	611612816	CML-RA	COMP	EQUIVALENT		
CYPD21342 (7CP64111C)	3612012	611612814	CML-RA	COMP	EQUIVALENT		
<b>YIELD: E-TEST</b>							
CYPD21342 (7CP64111C)	3612012	611612816	CML-RA	COMP	EQUIVALENT		
<b>YIELD: SORT</b>							
CYPD21342 (7CP64111C)	3612012	611612816	CML-RA	COMP	EQUIVALENT		



## Reliability Test Data

**QTP #: 164802**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: ACOUSTIC, MSL3</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	COMP	15	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	500	9	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	750	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	1000	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	1250	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	1500	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	1750	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	500	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	1100	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	2200	8	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	3300	3	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	4000	3	0	
<b>STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 6.6V), PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	96	28	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.27V, Vcc Max)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	48	1550	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.27V, Vcc Max)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	80	84	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	500	81	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	96	80	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	168	79	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	0	10+2	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	500	10+2	0	



## Reliability Test Data

**QTP #: 164802**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	COMP	6	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	COMP	3	0	
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	500	80	0	
CYPD21227 (7CP64102E)	3705058	611711793	CML-RA	1000	80	0	



## Reliability Test Data

**QTP #: 163301**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: DATA RETENTION, PLASTIC, 175C</b>							
CY8C4248AZI2 (8CP42003CB)	3621015	611619413	G-Taiwan	76	80	0	
CY8C4248AZI2 (8CP42003CB)	3621015	611619413	G-Taiwan	152	80	0	
<b>STRESS: ENDURANCE</b>							
CY8C4248AZI2 (8CP42003CB)	3621015	611619413	G-Taiwan	168	80	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	500	9	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	1000	3	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	1250	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	1000	3	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	2200	8	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	3300	3	0	
<b>STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	96	25	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	192	25	0	
CYPD3135 (7CP64301DB)	3652003	611700857	CML-RA	96	26	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.27V, Vcc Max)</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	48	1103	0	
CYPD3135 (7CP64301DB)	3641022	611637237	CML-RA	48	413	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	48	1570	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.27V, Vcc Max)</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	500	117	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	80	130	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	500	130	0	
<b>STRESS: HIGH TEMPERATURE STORAGE, PLASTIC, 150C</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	500	45	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	1000	45	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	500	45	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	1000	45	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	0	10+2	0	
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	500	10+2	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	0	10+2	0	
CYPD3135 (7CP64301DB)	3643014	611639672	CML-RA	500	10+2	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD3135 (7CP64301DB)	3652003	611700857	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3652003	611700858	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3706023	611706634	CML-RA	COMP	2	0	

## Reliability Test Data

**QTP #: 163301**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD3135 (7CP64301DB)	3652003	611700857	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3652003	611700858	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3706023	611706634	CML-RA	COMP	2	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD3135 (7CP64301DB)	3652003	611700857	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3652003	611700858	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD3135 (7CP64301DB)	3652003	611700857	CML-RA	COMP	6	0	
CYPD3135 (7CP64301DB)	3652003	611700858	CML-RA	COMP	6	0	
CYPD3135 (7CP64301DB)	3706023	611706634	CML-RA	COMP	6	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD3135 (7CP64301DB)	3652003	611700857	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3652003	611700858	CML-RA	COMP	3	0	
CYPD3135 (7CP64301DB)	3706023	611706634	CML-RA	COMP	2	0	
<b>STRESS: THERMAL JUNCTION MEASUREMENT</b>							
CYPD3135 (7CP64301DB)	3641047	611637169	CML-RA	COMP	1	0	



## Reliability Test Data

**QTP #: 164302**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: ACOUSTIC, MSL3</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	22	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	500	9	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	750	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	1000	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	1250	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	1500	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	1750	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	1100	9	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	2200	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	3300	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	4000	3	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	5000	3	0	
<b>STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	96	30	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.27V, Vcc Max)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	48	1040	1	Functional (NGDO_Vbus)
CYPD31357 (7CP64301JB)	3715132	611716236	CML-RA	48	1043	0	
CYPD31357 (7CP64301JB)	3719028	611719500	CML-RA	48	985	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.27V, Vcc Max)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	500	79	0	
<b>STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	168	79	0	
<b>STRESS: PRE/POST LFR PARAMETER ASSESSMENT</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	0	10+2	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	500	10+2	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	3	0	



## Reliability Test Data

**QTP #: 164302**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)</b>							
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	500	0	
CYPD31357 (7CP64301JB)	3714062	611714862	CML-RA	COMP	1000	0	



## Reliability Test Data

**QTP #: 162113**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
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**STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.16V, Vcc Max)**

CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	48	156	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	48	1515	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	48	744	0	
CYPD4226 (7CP64210A)	3650047	611647007	CML-RA	48	784	0	

**STRESS: ESD-CHARGE DEVICE MODEL**

CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	500	9	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	500	9	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	500	9	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	750	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	750	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	750	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	1000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	1000	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	1000	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	1250	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	1250	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	1250	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	1500	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	1500	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	1500	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	1750	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	1750	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	1750	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	2000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	2000	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	2000	3	0	

**STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114**

CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	1100	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	1100	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	1100	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	2200	8	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	2200	8	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	2200	8	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	3300	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	3300	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	3300	3	0	

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## Reliability Test Data

**QTP #: 162113**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	4000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	4000	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	4000	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	5000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	5000	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	5000	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	6000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	6000	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	6000	3	0	
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	7000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	7000	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	7000	3	0	
CYPD4226 (7CP64210A)	3631028	611627936	CML-RA	8000	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	COMP	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	COMP	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	COMP	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	COMP	3	0	
CYPD4226 (7CP64210A)	3649027	611645295	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD4226 (7CP64210A)	4628102	611623286	CML-RA	COMP	3	0	



## Reliability Test Data

**QTP #: 174801**

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: ACOUSTIC, MSL3</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	COMP	22	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 6.6V, Vcc Max)</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	48	1548	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	500	9	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	750	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	1000	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	1250	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	1500	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	1750	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	2000	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	500	9	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	750	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	1000	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	1250	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	1500	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	1750	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	1100	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	2200	8	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	3300	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	4000	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	5000	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	6000	3	0	
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	7000	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	1100	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	2200	8	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	3300	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	4000	3	0	

## Reliability Test Data

**QTP #: 174801**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp Rej</i>		<i>Failure Mechanism</i>
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	COMP	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	COMP	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	COMP	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	COMP	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD42267 (7CP64230A)	3745143	611746079	CML-RA	COMP	3	0	
CYPD4126 (7CP64234A)	3745143	611801313	CML-RA	COMP	3	0	



## Reliability Test Data

**QTP #: 174802**

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
<b>STRESS: ACOUSTIC, MSL3</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	COMP	22	0	
<b>STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.16V, Vcc Max)</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	48	547	0	
CYPD41257 (7CP64221A)	3804148	611804492	CML-RA	48	1044	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	500	9	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	750	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	1000	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	1250	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	1500	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	1750	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	2000	3	0	
<b>STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	1100	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	2200	8	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	3300	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	4000	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	5000	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	6000	3	0	
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	7000	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 100mA)</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (125C, 140mA)</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 140mA)</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 200mA)</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	COMP	3	0	
<b>STRESS: STATIC LATCH-UP (85C, 300mA)</b>							
CYPD42257 (7CP64220A)	3804148	611804493	CML-RA	COMP	3	0	



## Document History Page

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Rev.	ECN No.	Orig. of Change	Description of Change
**	6199884	JYF	Initial spec release.